Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/689,582	WEI, DAVID	
Examiner	**Art Unit**	
Nhan T. Tran	2622	

SEARCHED			
Class	Subclass	Date	Examiner
348	373 375	2/1/2007	NT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
PGPUB text search - see search history printout		2/4/2007	NT

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB) text search - see search history printout	2/1/2007	NT
348/373-376 (text search - see search history printout)	2/1/2007	NT
348/211.1-211.14 (text search - see search history printout)	2/1/2007	NT
396/419, 427, 428 (text search - see search history printout)	2/2/2007	NT
348/14.01-14.16, 143 (text search - see search history printout)	2/4/2007	NT
text search all classes - see search history printout	2/4/2007	NT
Inventorship search - see search history printout	**2/4/2007**	**NT**